

MOS FIELD EFFECT TRANSISTOR μ PA1917

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1917 is a switching device which can be driven directly by a 1.8 V power source.

This device features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- 1.8 V drive available
- Low on-state resistance

RDS(on)1 = $53 \text{ m}\Omega \text{ MAX}$. (Vgs = -4.5 V, ID = -3.0 A)

RDS(on)2 = $70 \text{ m}\Omega \text{ MAX}$. (Vgs = -2.5 V, ID = -3.0 A)

 $R_{DS(on)3} = 107 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -1.8 \text{ V, Ip} = -1.5 \text{ A)}$

ORDERING INFORMATION

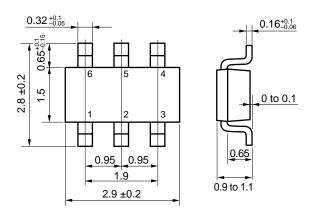
PART NUMBER	PACKAGE
μPA1917TE	SC-95 (Mini Mold Thin Type)

Marking: TR

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

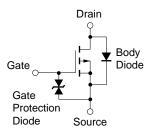
Drain to Source Voltage (Vss = 0 V)	VDSS	-20	V
Gate to Source Voltage (Vps = 0 V)	Vgss	∓8.0	V
Drain Current (DC) (T _A = 25°C)	I _{D(DC)}	∓6.0	Α
Drain Current (pulse) Note1	D(pulse)	∓24	Α
Total Power Dissipation	P _{T1}	0.2	W
Total Power Dissipation Note2	P _{T2}	2.0	W
Channel Temperature	T_ch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

PACKAGE DRAWING (Unit: mm)



1, 2, 5, 6 : Drain 3 : Gate 4 : Source

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on FR-4 board, $t \le 5$ sec.

Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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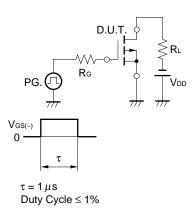
Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

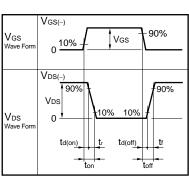


ELECTRICAL CHARACTERISTICS (TA = 25°C)

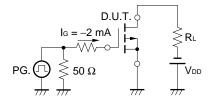
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = -20 V, V _{GS} = 0 V			-10	μΑ
Gate Leakage Current	Igss	V _G S = ∓8.0 V, V _D S = 0 V			∓10	μΑ
Gate to Source Cut-off Voltage	VGS(off)	V _{DS} = -10 V, I _D = -1.0 mA	-0.45	-0.75	-1.5	V
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -3.0 A	5.0	10.4		S
Drain to Source On-state Resistance	RDS(on)1	V _{GS} = -4.5 V, I _D = -3.0 A		42	53	mΩ
	RDS(on)2	V _G S = -2.5 V, I _D = -3.0 A		52	70	mΩ
	RDS(on)3	V _G S = -1.8 V, I _D = -1.5 A		64	107	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		835		pF
Output Capacitance	Coss	V _G s = 0 V		170		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		99		pF
Turn-on Delay Time	t d(on)	$V_{DD} = -10 \text{ V}, \text{ ID} = -3.0 \text{ A}$		16		ns
Rise Time	tr	V _{GS} = -4.0 V		64		ns
Turn-off Delay Time	td(off)	$R_G = 10 \Omega$		78		ns
Fall Time	tf			108		ns
Total Gate Charge	Q _G	V _{DD} = -16 V		8.1		nC
Gate to Source Charge	Qgs	V _{GS} = -4.0 V		1.3		nC
Gate to Drain Charge	Q _{GD}	I _D = -6.0 A		2.8		nC
Diode Forward Voltage	V _{F(S-D)}	IF = 6.0 A, VGS = 0 V		0.94		V

TEST CIRCUIT 1 SWITCHING TIME

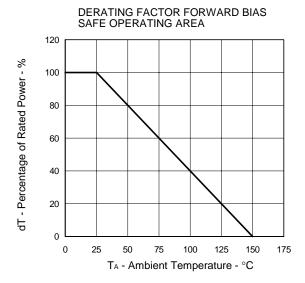




TEST CIRCUIT 2 GATE CHARGE



TYPICAL CHARACTERISTICS (TA = 25°C)



AMBIENT TEMPERATURE 2.4 2 1.6 1.6 0.8 0.4 0.4

TOTAL POWER DISSIPATION vs.

T_A - Ambient Temperature - °C

100

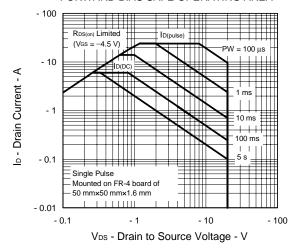
125

150

175

75

FORWARD BIAS SAFE OPERATING AREA



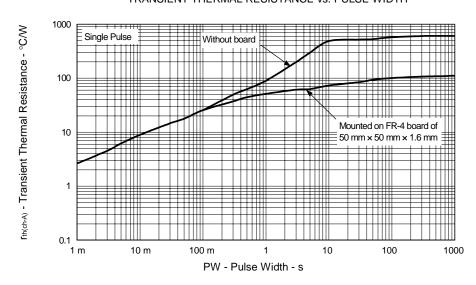


0

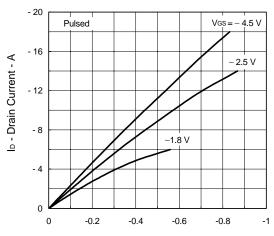
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25

50

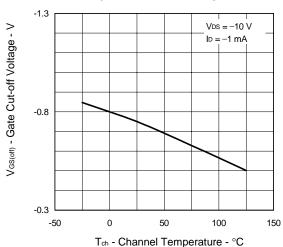


DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE

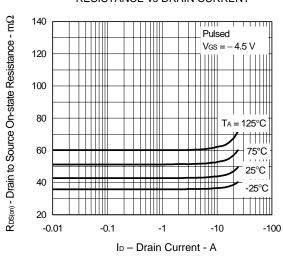


V_{DS} - Drain to Source Voltage - V

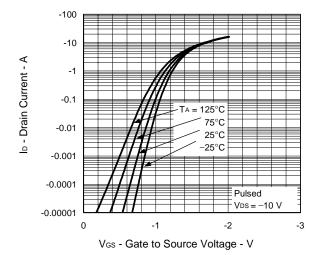
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



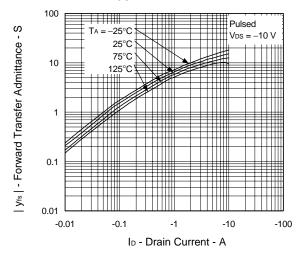
DRAIN TO SOURCE ON-STATE RESISTANCE vs DRAIN CURRENT



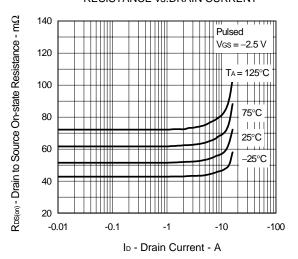
FORWARD TRANSFER CHARACTERISTICS



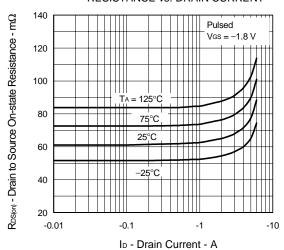
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



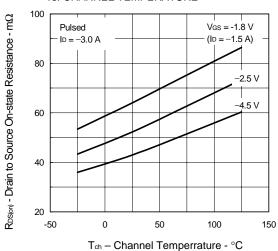
DRAIN TO SOURCE ON-STATE RESISTANCE vs.DRAIN CURRENT



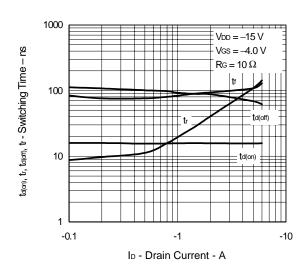
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



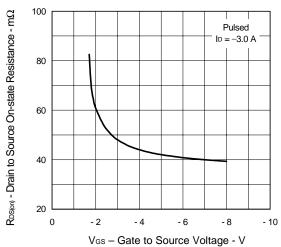
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



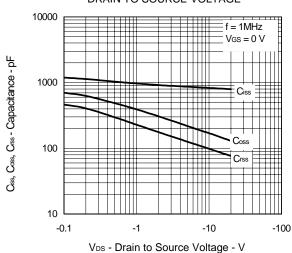
SWITCHING CHARACTERISTICS



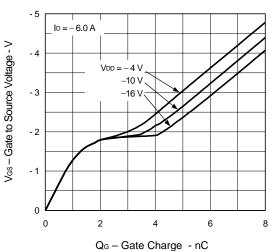
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



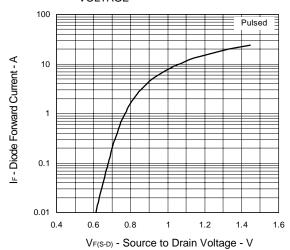
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE





[MEMO]

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